NPC

OVERVIEW

The SM5021 series are crystal oscillator module ICs fabricated in NPC's Molybdenum-gate CMOS, that incorporate high-frequency, low current consumption oscillator and output buffer circuits. Highly accurate thin-film feedback resistors and high-frequency capacitors are built-in, eliminating the need for external components to make a stable 3rd overtone oscillator.

FEATURES

- 3rd overtone oscillation
- Oscillator capacitors C_G, C_D built-in
- Inverter amplifier feedback resistor built-in $(A \times, B \times \text{series})$
- TTL input level
- Output drive capability
- 4mA (V_{DD} = 2.7V)
 8mA (V_{DD} = 4.5V)

SERIES CONFIGURATION

- Output three-state function
- Operating supply voltage range
 - 2.7 to 5.5V (A×, K× series)
- 4.5 to 5.5V (B×, L× series)
- Oscillator frequency output
- 6-pin SOT (SM5021××H)
- Chip form (CF5021 \times)

Version ^{*1}		Operating supply voltage range [V]		mended frequency ² [MHz]	Built-in capacitance [pF]		gm ratio	Rf [kΩ]	Output frequency	Output	Standby output state
	Chip	SOT	3V operation	5V operation	C _G	CD	Tallo	[K32]	irequency	level	State
SM5021AAH	4.5 to 5.5	4.5 to 5.5	×	22 to 30			1	6.0			
SM5021ABH			22 to 30	30 to 43		15	1	3.3			
SM5021ACH	2.7 to 5.5	2.7 to 5.5	30 to 40	43 to 55	8	15	2	3.9	fo	CMOS	High impedance
SM5021ADH			40 to 50	55 to 70			3	2.7			
SM5021AEH	2.7 to 3.6	×	50 to 70	×		12	4	2.7			
SM5021BAH				22 to 30			1	6.0			
SM5021BBH	4.5 to 5.5	4.5 to 5.5		30 to 43	8	15	1	3.3	fo	TTL	Lich impodonoo
SM5021BCH	4.5 10 5.5	4.5 10 5.5	×	43 to 55	0	15	2	3.9	10	116	High impedance
SM5021BDH				55 to 70			3	2.7			
SM5021KDH	2.7 to 5.5	2.7 to 5.5	22 to 50 ^{*3}	22 to 70 ^{*3}	8	15	3		fo	CMOS	High impodance
SM5021KEH	2.7 to 3.6	2.7 to 3.6	50 to 70 ^{*3}	×	ð	12	4	-	10	CIVIUS	High impedance
SM5021LDH	4.5 to 5.5	4.5 to 5.5	×	22 to 70 ^{*3}	8	15	3	-	fo	TTL	High impedance

*1. Chip form devices have designation CF5021××.

*2. The recommended operating frequency is a vardstick value derived from the crystal used for NPC characteristics authentication. However, the oscillator frequency band is not guaranteed. Specifically, the characteristics can vary greatly due to crystal characteristics and mounting conditions, so the oscillation characteristics of components must be carefully evaluated.

*3. The 3rd overtone frequency range using an external resistor to set the cutoff frequency.

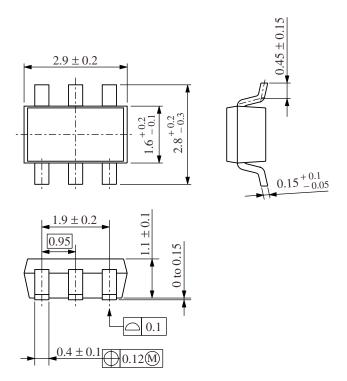
ORDERING INFORMATION

Device	Package
SM5021××H	SOT23-6
CF5021××-2	Chip form

PACKAGE DIMENSIONS

(Unit: mm)

• 6-pin SOT

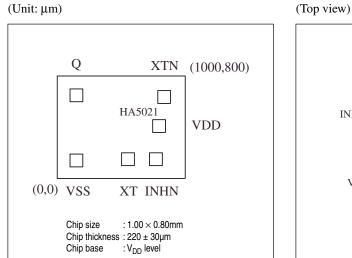


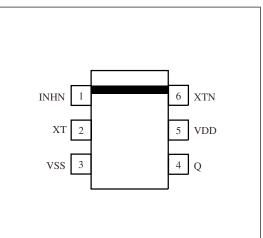
SM5021 series

PAD LAYOUT

PINOUT



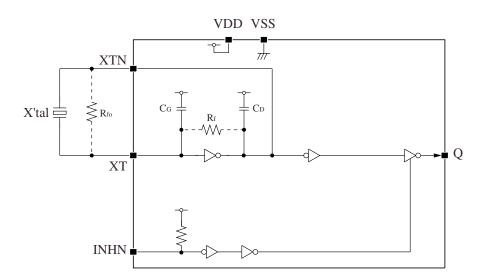




PIN DESCRIPTION and PAD DIMENSIONS

Number	Name	1/0		Description		
Number	Name	1/0		Description	X	Y
1	INHN	I	Output state control	input. High impedance when LOW. Pull-up resistor built in	771	150
2	ХТ	I	Amplifier input.	Amplifier input. Crystal oscillator connection pins. Crystal oscillator is connected between XT and XTN		150
3	VSS	-	Ground		150	140
4	Q	0	Output. Output frequ	iency (f _O)	150	649
5	VDD	-	Supply voltage	Supply voltage		409
6	XTN	0	Amplifier output.	Crystal oscillator connection pins. Crystal oscillator is connected between XT and XTN	836	636

BLOCK DIAGRAM



SPECIFICATIONS

Absolute Maximum Ratings

 $V_{SS} = 0V$

Parameter	Symbol	Condition	Rating	Unit
Supply voltage range	V _{DD}		- 0.5 to + 7.0	V
Input voltage range	V _{IN}		- 0.5 to V _{DD} + 0.5	V
Output voltage range	V _{OUT}		- 0.5 to V _{DD} + 0.5	
Operating temperature range	T _{opr}		- 40 to + 85	°C
Storage temperature renge	т	Chip form	- 65 to + 150	- °C
Storage temperature range	T _{stg}	SOT23-6	- 55 to + 125	
Output current	I _{OUT}		13	mA
Power dissipation	PD	SOT23-6	250	mW

Recommended Operating Conditions

 $V_{SS} = 0V$, $f \le 70MHz$, $C_L \le 15pF$

Parameter	Symbol	Condition		Rating		Unit
Falameter	Symbol	Condition	min	typ	max	Onit
Supply voltage	V _{DD}		2.7	-	5.5	V
Input voltage	V _{IN}		V _{SS}	-	V _{DD}	V
Operating temperature	T _{OPR}		- 20	-	+ 80	°C

Note: Recommended operating conditions will change in accordance with operating frequency, load capacitance, or power dissipation.

Electrical Characteristics

3V operation: AA, AB, AC, AD, AE, KD, KE series

 V_{DD} = 2.7 to 3.6V, V_{SS} = 0V, Ta = - 20 to + 80°C unless otherwise noted.

Parameter	Sumbol	Condition			Rating		Unit
Parameter	Symbol	Condition	n	min	typ	max	Unit
HIGH-level output voltage	V _{OH}	Q: Measurement cct 1, V_{DD} = 2.7V, I_{OH} = 4mA	SM5021×AH, CF5021×A SM5021×BH, CF5021×B SM5021×CH, CF5021×C SM5021×CH, CF5021×C	2.1	2.4	_	V
		Q: Measurement cct 1, V_{DD} = 2.7V, I_{OH} = 8mA	SM5021×EH, CF5021×E				
LOW-level output voltage	V _{OL}	Q: Measurement cct 2, V_{DD} = 2.7V, I_{OL} = 4mA	SM5021×AH, CF5021×A SM5021×BH, CF5021×B SM5021×CH, CF5021×C SM5021×DH, CF5021×D	_	0.3	0.4	V
		Q: Measurement cct 2, V_{DD} = 2.7V, I _{OL} = 8mA	SM5021×EH, CF5021×E				
HIGH-level input voltage	V _{IH}	INHN		2.0	-	-	V
LOW-level input voltage	VIL	INHN		-	-	0.5	V
Outrast la classica comment	1_	Q: Measurement cct 2, V_{DD} = 3.3V, INHN = LOW, V_{OH} = V_{DD}		-	-	10	μA
Output leakage current	Iz	Q: Measurement cct 2, V _{DD} = 3.3V, IN	NHN = LOW, V _{OL} = V _{SS}	-	-	10	μΑ
Current consumption	I _{DD}	70MHz crystal oscillator, measurement cct 3, load cct 1, INHN = open, C _L = 15pF	SM5021A×H, CF5021A× SM5021K×H, CF5021K×	-	13	25	mA
INHN pull-up resistance	R _{UP}	Measurement cct 4	•	25	100	250	kΩ
			SM5021×AH, CF5021×A	5.1	6.0	6.9	
Feedback resistance			SM5021×BH, CF5021×B	2.8	3.3	3.8	
(A× series only)	R _f	Measurement cct 5	SM5021×CH, CF5021×C	3.3	3.9	4.5	kΩ
			SM5021×DH, CF5021×D SM5021×EH, CF5021×E	2.3	2.7	3.1	
	C _G	Design value. A monitor pattern on a	wafer is tested.	7.44	8	8.56	pF
Built-in capacitance	CD	Design value. A monitor pattern on a wafer is tested.	SM5021×AH, CF5021×A SM5021×BH, CF5021×B SM5021×CH, CF5021×C SM5021×CH, CF5021×C	13.95	15	16.05	pF
		SM5021×EH, CF5021×E		11.16	12	12.84	1

5V operation: AA, AB, AC, AD, BA, BB, BC, BD, KD, LD series

 V_{DD} = 4.5 to 5.5V, V_{SS} = 0V, Ta = - 20 to + 80°C unless otherwise noted.

Parameter	Cumhal	Conditio	_		Rating		Unit
Parameter Symbol		Condition	Condition			max	Unit
HIGH-level output voltage	V _{OH}	Q: Measurement cct 1, V _{DD} = 4.5V, I _C	_{DH} = 8mA	3.9	4.2	-	V
LOW-level output voltage	V _{OL}	Q: Measurement cct 2, V _{DD} = 4.5V, I _C	_{DL} = 8mA	-	0.3	0.4	V
HIGH-level input voltage	V _{IH}	INHN		2.0	_	-	V
LOW-level input voltage	VIL	INHN		-	-	0.8	V
		Q: Measurement cct 2, V _{DD} = 5.5V, IN	NHN = LOW, V _{OH} = V _{DD}	-	-	10	
Output leakage current	Iz	Q: Measurement cct 2, V _{DD} = 5.5V, IN	NHN = LOW, V _{OL} = V _{SS}	-	-	10	μA
Current consumption	I _{DD}	70MHz crystal oscillator, measurement cct 3, load cct 1, INHN = open, C _L = 15pF	SM5021AAH, CF5021AA SM5021ABH, CF5021AB SM5021ACH, CF5021AC SM5021ACH, CF5021AC SM5021ADH, CF5021AD SM5021KDH, CF5021KD	_	18	35	mA
		70MHz crystal oscillator, measurement cct 3, load cct 2, INHN = open, C _L = 15pF	SM5021B×H, CF5021B× SM5021L×H, CF5021L×	-	18	35	
INHN pull-up resistance	R _{UP}	Measurement cct 4		25	100	250	kΩ
			SM5021×AH, CF5021×A	5.1	6.0	6.9	
Feedback resistance		Measurement cct 5	SM5021×BH, CF5021×B	2.8	3.3	3.8	10
(A×, B× series only)	R _f	measurement cct 5	SM5021×CH, CF5021×C	3.3	3.9	4.5	kΩ
			SM5021×DH, CF5021×D	2.3	2.7	3.1	
	C _G		SM5021×AH, CF5021×A	7.44	8	8.56	pF
Built-in capacitance	CD	Design value. A monitor pattern on a wafer is tested.	SM5021×BH, CF5021×B SM5021×CH, CF5021×C SM5021×DH, CF5021×D	13.95	15	16.05	pF

Switching Characteristics

CMOS Output Version

3V operation: AA, AB, AC, AD, AE, KD, KE series

 V_{DD} = 2.7 to 3.6V, V_{SS} = 0V, Ta = -20 to + 80°C unless otherwise noted.

Parameter	Sumbol	Condition	Condition				Unit
Parameter	Symbol	Condition		min	typ	max	Unit
		Measurement cct 6, load cct 1, $0.1V_{DD}$ to $0.9V_{DD}$, $C_L = 15pF$	SM5021AAH, CF5021AA SM5021ABH, CF5021AB SM5021ACH, CF5021AC SM5021ACH, CF5021AC SM5021ADH, CF5021AD SM5021KDH, CF5021KD	_	5	10	
Output rise time	t _{r1}		SM5021AEH, CF5021AE SM5021KEH, CF5021KE	-	3.5	7	ns
		Measurement cct 6, load cct 1, $0.2V_{DD}$ to $0.8V_{DD}$, $C_L = 15pF$	SM5021AAH, CF5021AA SM5021ABH, CF5021AB SM5021ACH, CF5021AC SM5021ACH, CF5021AC SM5021ADH, CF5021AD SM5021KDH, CF5021KD	_	3.5	7	•
		Measurement cct 6, load cct 1, $0.9V_{DD}$ to $0.1V_{DD}$, $C_L = 15pF$	SM5021AAH, CF5021AA SM5021ABH, CF5021AB SM5021ACH, CF5021AC SM5021ACH, CF5021AC SM5021ADH, CF5021AD SM5021KDH, CF5021KD	_	5	10	
Output fall time	t _{f1}		SM5021AEH, CF5021AE SM5021KEH, CF5021KE	-	3.5	7	ns
		Measurement cct 6, load cct 1, $0.8V_{DD}$ to $0.2V_{DD}$, $C_L = 15pF$	SM5021AAH, CF5021AA SM5021ABH, CF5021AB SM5021ACH, CF5021AC SM5021ACH, CF5021AC SM5021ADH, CF5021AD SM5021KDH, CF5021KD	_	3.5	7	
Output duty cycle ^{*1}	Duty	Measurement cct 6, load cct 1, V_{DD} = 3V, Ta = 25°C, C _L = 15pF, f ≤ 70MHz		45	-	55	%
Output disable delay time	t _{PLZ}	Measurement cct 6, load cct 1, V _{DD} = 3	W To - 25°C C - 15rF	-	-	100	ns
Output enable delay time	t _{PZL}	$\frac{1}{1000} = 3$	ν, ια - 20 0, 0[= 10μΓ	-	-	100	ns

 $^{\ast}\ensuremath{\text{1.}}$ The duty cycle characteristic is checked the sample chips of each production lot.

5V operation: AA, AB, AC, AD, KD series

 V_{DD} = 4.5 to 5.5V, V_{SS} = 0V, Ta = -20 to + 80°C unless otherwise noted.

Parameter	Cumhal	Condition		Rating		Unit
Parameter	Symbol	Condition	min	typ	max	
Output rise time	t _{r1}	Measurement cct 6, load cct 1, $0.1V_{DD}$ to $0.9V_{DD}$, $C_L = 15pF$	-	3.5	7	ns
Output fall time	t _{f1}	Measurement cct 6, load cct 1, $0.9V_{DD}$ to $0.1V_{DD}$, $C_L = 15pF$	-	3.5	7	ns
Output duty cycle ^{*1}	Duty	Measurement cct 6, load cct 1, V _{DD} = 5V, Ta = 25°C, C _L = 15pF, $f \le 70MHz$	45	-	55	%
Output disable delay time	t _{PLZ}	Measurement cct 6, load cct 1, V_{DD} = 5V, Ta = 25°C, C ₁ = 15pF	I	-	100	ns
Output enable delay time	t _{PZL}	$v_{DD} = 5v$, $a = 25^{\circ}$ C, $C_L = 15pr$	-	-	100	ns

*1. The duty cycle characteristic is checked the sample chips of each production lot.

TTL Output Version

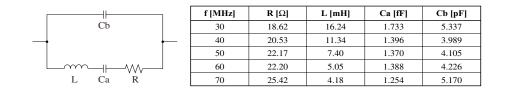
5V operation: BA, BB, BC, BD, LD series

 $V_{DD} = 4.5$ to 5.5V, $V_{SS} = 0V$, Ta = -20 to $+ 80^{\circ}C$ unless otherwise noted.

Parameter	Sumbol	Condition		Rating		Unit
Parameter	Symbol	Condition	min	typ	max	
Output rise time	t _{r2}	Measurement cct 6, load cct 2, 0.4V to 2.4V, C _L = 15pF	-	2.5	7	ns
Output fall time	t _{f2}	Measurement cct 6, load cct 2, 2.4V to 0.4V, C _L = 15pF	-	2.5	7	ns
Output duty cycle ^{*1}	Duty	Measurement cct 6, load cct 2, V _{DD} = 5V, Ta = 25°C, C _L = 15pF, f \leq 70MHz	45	-	55	%
Output disable delay time	t _{PLZ}		I	-	100	ns
Output enable delay time	t _{PZL}	Measurement cct 6, load cct 2, V _{DD} = 5V, Ta = 25°C, C _L = 15pF	-	-	100	ns

*1. The duty cycle characteristic is checked the sample chips of each production lot.

Current consumption and Output waveform with NPC's standard crystal



FUNCTIONAL DESCRIPTION

Standby Function

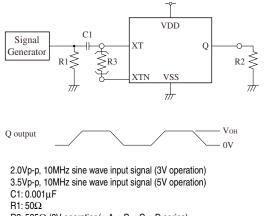
When INHN goes LOW, the oscillator output on Q goes high impedance.

INHN	Q	Oscillator
HIGH (or open)	f _O	Normal operation
LOW	High impedance	Normal operation

MEASUREMENT CIRCUITS

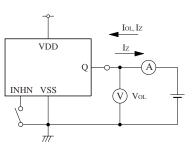
Measurement cct 1

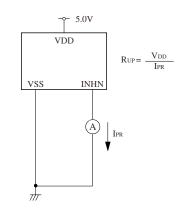
Measurement cct 4



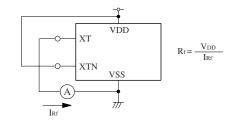
 $\begin{array}{l} \text{R2: } 525\Omega \; (3\text{V operation}/ \times \text{A}, \times \text{B}, \times \text{C}, \times \text{D series}) \\ 263\Omega \; (3\text{V operation}/ \times \text{E series}) \\ 490\Omega \; (5\text{V operation}) \\ \text{R3: } 100 \text{k}\Omega \; (\text{K}\times, \text{L}\times \text{series}) \end{array}$



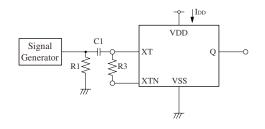




Measurement cct 5

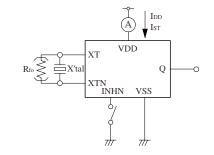


Measurement cct 3

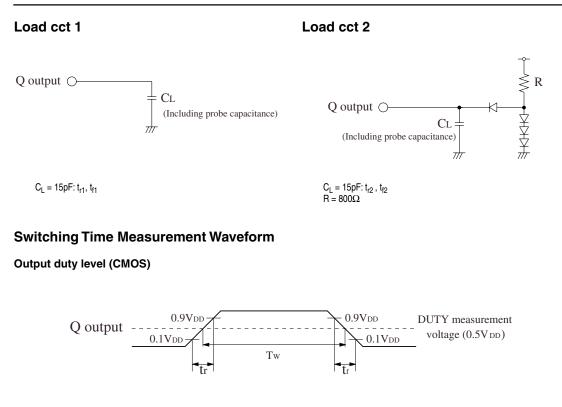


2.0Vp-p, 70MHz sine wave input signal (3V operation) 3.5Vp-p, 70MHz sine wave input signal (5V operation) C1: $0.001 \mu F$ R1: 50Ω R3: $100k\Omega$ (K×, L× series)

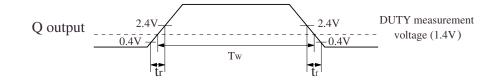
Measurement cct 6

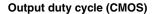


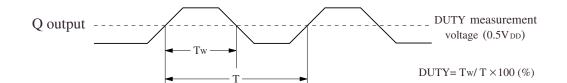
 $\mathsf{R}_{fo}:$ 2.7k Ω (K×, L× series)



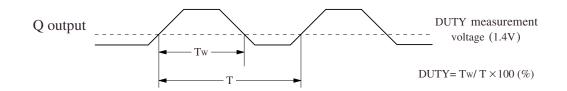
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Output duty level (TTL)
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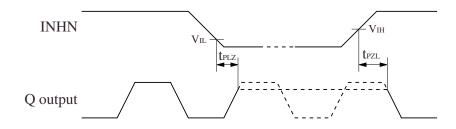




Output duty cycle (TTL)



Output Enable/Disable Delay



INHN input waveform $tr = tf \le 10ns$

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NC9903CE 2006.04